

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/040,898	BAE, JONG-HONG	
Examiner	Art Unit	
Tse Chen	2116	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
713/1,100,500 WITH TEXT SEARCY: SEE SECH CPT PRIOUT	11/29/05	756	